

## IN THE CLAIMS

Per the revised amendment practice, a complete listing of all claims in the application follows.

1. (Original) A method of testing a memory die, comprising:  
allowing said memory die to be placed in a location outside of a production facility  
of said die;  
testing said memory die while said die is in said location; and  
storing a partial memory cell address on said die as a result of said testing act,  
wherein said address corresponds to a memory cell having failed said testing act.
2. (Original) The method in claim 1, wherein said testing act comprises testing said die while  
said die is part of an electronic system.
3. (Original) The method in claim 2, wherein said testing act comprises testing said die while  
said electronic system is in a power management mode.
4. (Original) The method in claim 2, wherein said testing act comprises testing said die while  
said die is part of a computer system.
5. (Original) The method in claim 2, wherein said testing act comprises testing said die while  
said die is part of a telephone system.
6. (Original) The method in claim 5, wherein said testing act comprises testing said die while  
said die is part of a cellular telephone system.

Claims 7-57 (Cancelled).